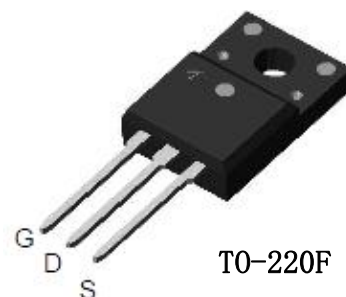


500V N-Channel MOSFET

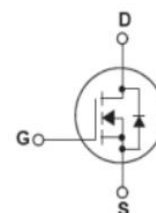
Features

- $V_{DSS}=500V$ $I_D=13A$
 $R_{DS(ON)}=0.5\Omega(\text{Max.})@V_{GS}=10V$
- High Reliability Capability with Passivation
- 100% avalanche tested
- RoHS compliant
- Smart design in high voltage technology.

PIN DESCRIPTION



TO-220F



Applications

- LED power supplies
- Cell Phone Charger
- Standby Power

Part Number	Package	Marking	ROHS Status	Packing
SI13N50F	TO-220F	SI13N50F	Pb-Free	Box (Tube)

Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Typical	Unit
V_{DSS}	Drain-Source Voltage	500	V
V_{GSS}	Gate-Source Voltage	± 30	V
I_D	Drain Current	TC=25°C	13
		TC=100°C	6.5
I_{DM}	Pulsed Drain Current	50	A
P_D	Power Dissipation (TC = 25°C)	42	W
I_{AR}	Avalanche Current	5.5	A
E_{AS}	Single Pulse Avalanche Energy	904	mJ
E_{AR}	Repetitive Avalanche Energy	454	mJ
T_J, T_{stg}	Operating Junction and Storage Temperature Range	-55 to 150	°C

Thermal Resistance

Parameter	Symbol	Value	Unit
Thermal resistance, junction – case.	$R_{\theta JC}$	2.5	°C/W
Thermal resistance, junction – ambient.	$R_{\theta JA}$	62	

Electrical Characteristics ($T_A=25^\circ\text{C}$ unless otherwise noted)

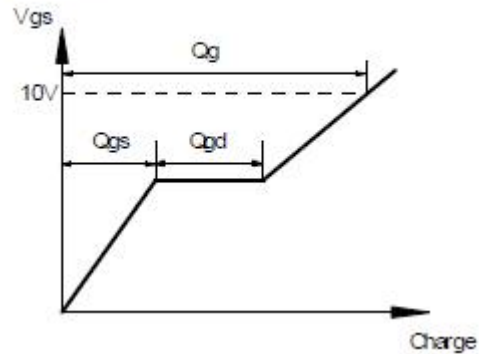
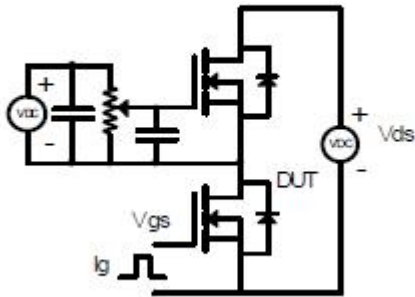
Symbol	Parameter	Test Conditions	Min	TYP	Max	Unit
Static Characteristics						
BV_{DSS}	Drain-source breakdown voltage	$V_{GS}=0V, I_D=250\mu A$	500	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=500V, V_{GS}=0V$	-	-	1	μA
I_{GSS}	Gate-Source Leakage	$V_{GS}=\pm 30V, V_{DS}=0V$	-	-	± 100	nA
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2	-	4	V
$R_{DS(on)}$	Drain-Source On-Resistance	$V_{GS}=10V, I_D=6.5A$	-	-	0.5	Ω
g_{fs}	Forward Transconductance	$V_{DS}=40V, I_D=6.5A$	-	13	-	S
Dynamic Characteristic						
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=25V, f=1MHz$	-	1361	-	pF
C_{oss}	Output Capacitance		-	167	-	
C_{rss}	Reverse Transfer Capacitance		-	12.6	-	
Q_G	Gate Total Charge	$V_{DS}=400V, I_D=13A, V_{GS}=10V,$	-	30.7	-	nC
Q_{gs}	Gate-Source charge		-	7.6	-	
Q_{gd}	Gate-Drain charge		-	13	-	
$t_{d(on)}$	Turn-on delay time	$V_{DD}=250V, I_D=13A, R_G=25\Omega, V_{GS}=10V$	-	29	-	nS
t_r	Rise time		-	69	-	
$t_{d(off)}$	Turn-off delay time		-	82	-	
t_f	Fall time		-	55	-	
Drain-Source Body Diode Characteristics						
V_{SD}	Body Diode Forward Voltage	$V_{GS}=0V, I_F=1A$	-	-	1.4	V
t_{rr}	Body Diode Reverse Recovery Time	$V_R=100V, I_F=13A, di_F/dt=100A/\mu s$	-	-	550	nS
Q_{rr}	Body Diode Reverse Recovery Charge		-	4.5	-	nC
I_S	Maximum Continuous Drain-Source Diode Forward Current		-	-	13	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current		-	-	48	A

Note:

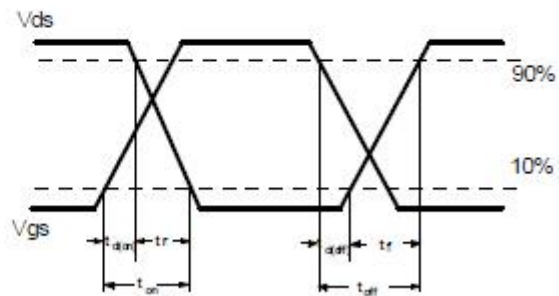
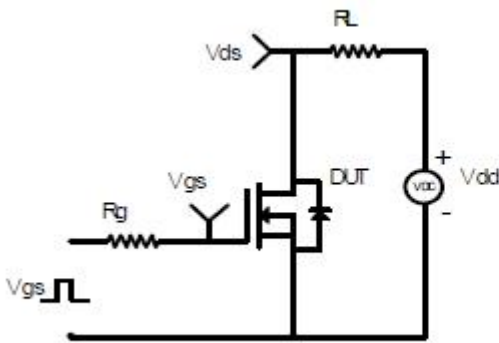
- The value of $R_{\theta JA}$ is measured with the device in a still air environment with $T_A=25^\circ\text{C}$.
- The static characteristics in Figures 1 to 6 are obtained using $<300\mu s$ pulses, duty cycle 2% max

Switching Time Test Circuit and Wave forms

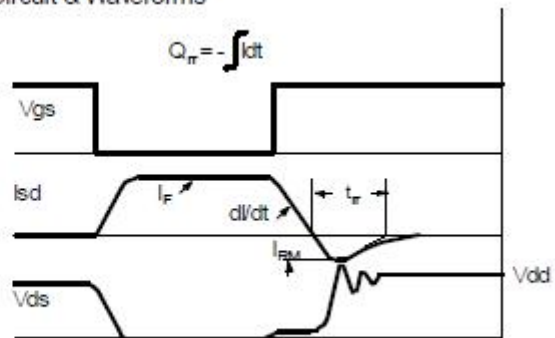
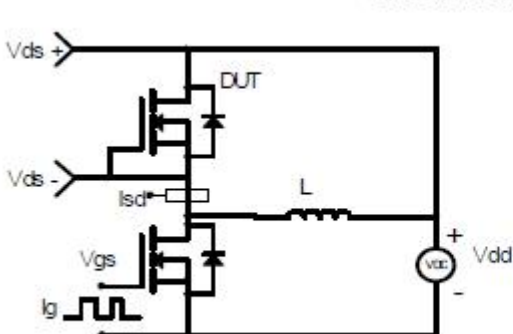
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Typical Performance Characteristics

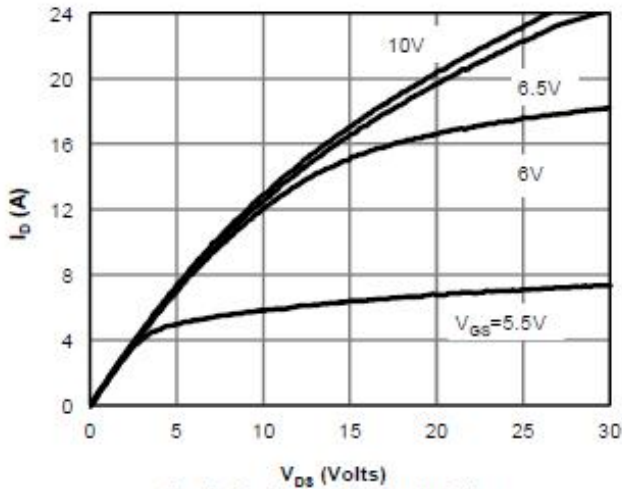


Fig 1: On-Region Characteristics

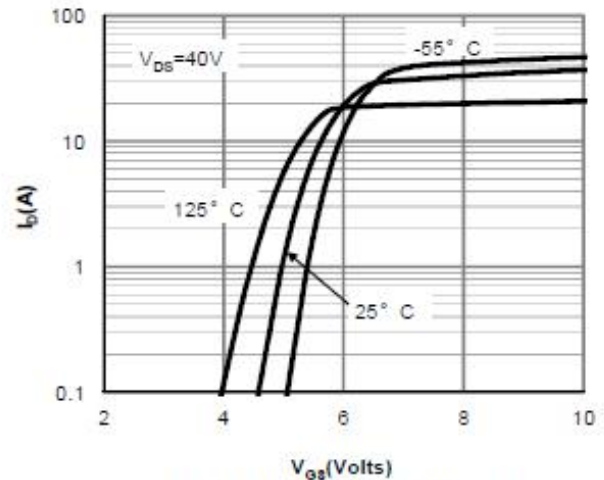


Figure 2: Transfer Characteristics

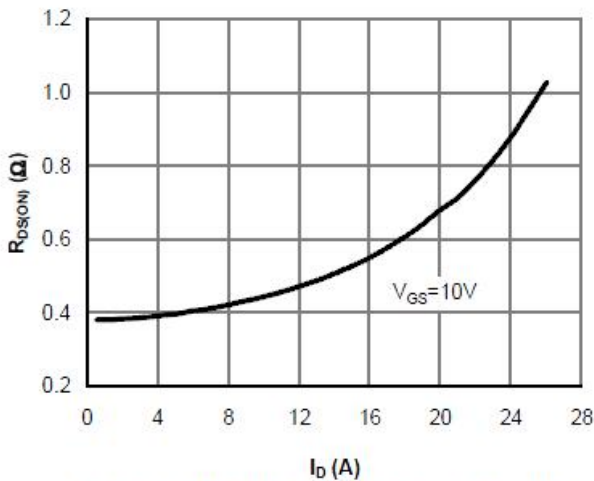


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

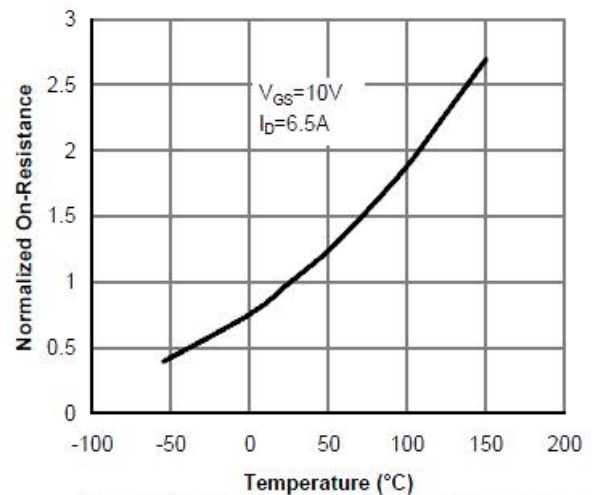


Figure 4: On-Resistance vs. Junction Temperature

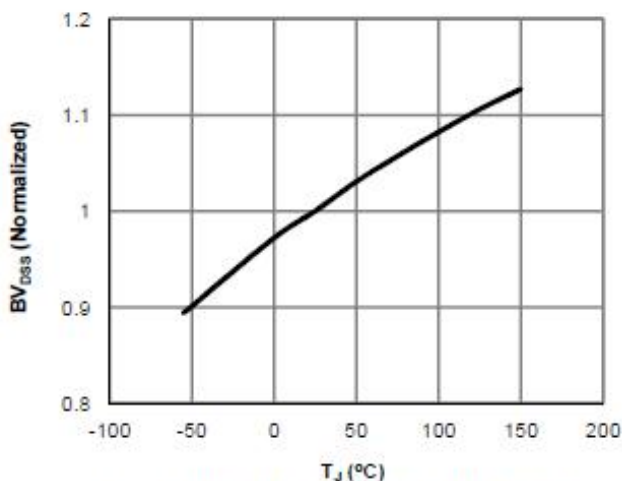


Figure 5: Break Down vs. Junction Temperature

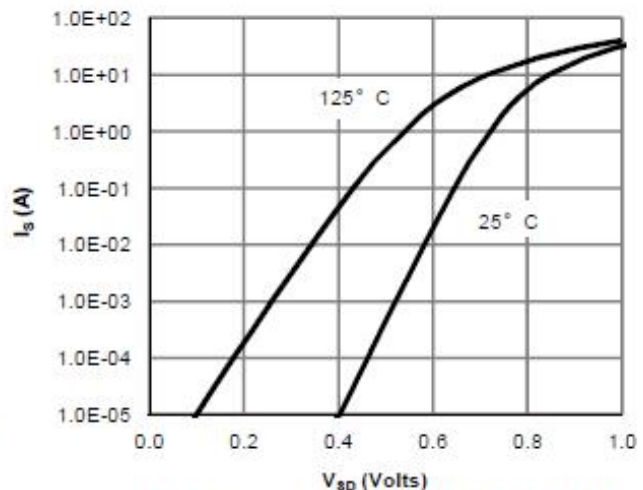
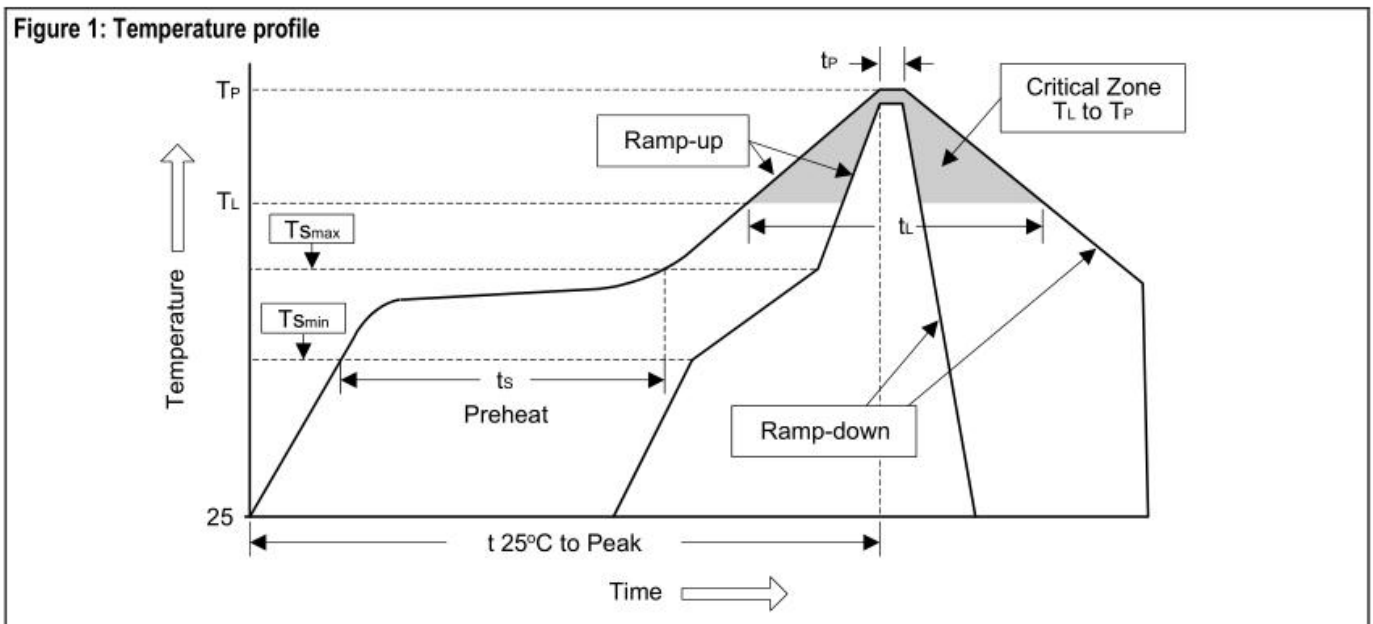


Figure 6: Body-Diode Characteristics (Note E)

Soldering Methods for Products

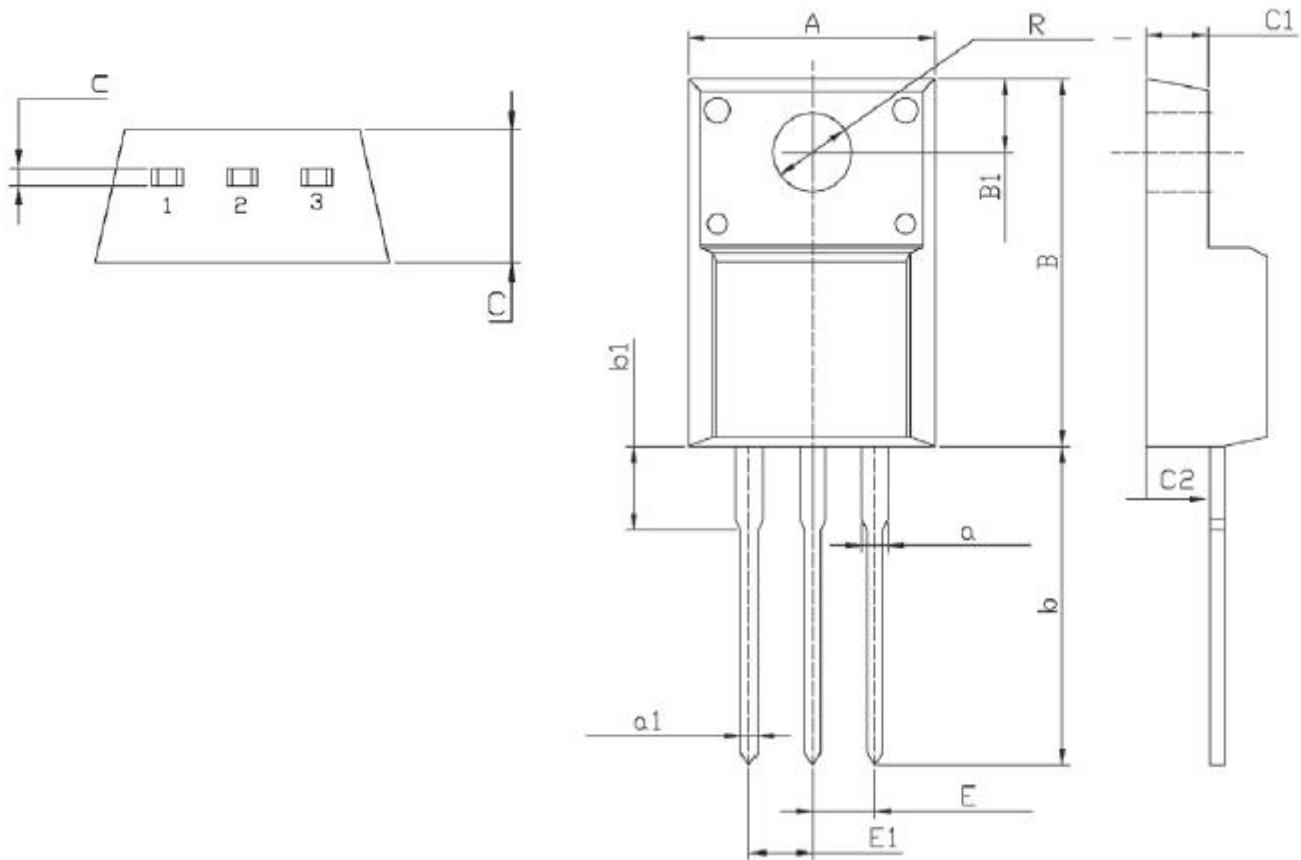
Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate(TL to TP)	<3°C/sec	<3°C/sec
Preheat -Temperature Min(Ts min) -Temperature Max(Ts max) -Time(min to max)(ts)	100°C 150°C 60 to 120 sec	150°C 200°C 60 to 180 sec
Tsmax to TL - ramp-up rate	<3°C/sec	<3°C/sec
Time maintained above: -Temperature(TL) -Time(tL)	183°C 60 to 150 sec	217°C 60 to 150 sec
Peak Temperature(Tp)	240°C+0/-5°C	250°C+0/-5°C
Time within 5°C of actual Peak Temperature	10 to 30 sec	20 to 40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25 °C to Peak Temperature	<6 minutes	<8 minutes



Note :1.Storage environment: Temperature=10°C to 35@Humidity=45%±15%

- 2.Reflow soldering of surface-mount devices
- 3.Flow(wave) soldering(solder dipping)

Products	Peak Temperature	Dipping Time
Pb devices	245°C±5°C	5sec±1sec
Pb-free devices	250°C+0/-5°C	5sec±1sec

Package Outline


Millimeter					
Symbol	Min	Max	Symbol	Min	Max
C	4.5	4.9	b1	2.90	3.90
c	0.4	0.6	a	1.08	1.48
A	9.96	10.36	a1	0.70	0.90
B	15.67	16.07	E	2.34	2.74
B1	3.30	3.50	E1	2.34	2.74
R	3.08	3.28	C1	2.34	2.74
b	12.48	13.48	C2	2.56	2.96

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